

# **AVX Surface Mount Ceramic Capacitor Products**

# <span id="page-1-0"></span>**Ceramic Chip Capacitors**

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AVAX



#### <span id="page-2-0"></span>**Commercial Surface Mount Chips EXAMPLE: 08055A101JAT2A**



#### **High Voltage Surface Mount Chips EXAMPLE: 1808AA271KA11A**





## **How to Order Part Number Explanation**



#### **Capacitor Array**

#### **EXAMPLE: W2A43C103MAT2A**



### **Low Inductance Capacitors (LICC)**

### **EXAMPLE: 0612ZD105MAT2A**



### **Interdigitated Capacitors (IDC)**





#### **Decoupling Capacitor Arrays (LICA) EXAMPLE: LICA3T183M3FC4AA**





### <span id="page-4-0"></span>**General Specifications**



C0G (NP0) is the most popular formulation of the "temperature-compensating," EIA Class I ceramic materials. Modern C0G (NP0) formulations contain neodymium, samarium and other rare earth oxides.

C0G (NP0) ceramics offer one of the most stable capacitor dielectrics available. Capacitance change with temperature is 0 ±30ppm/°C which is less than ±0.3% ∆ C from -55°C to +125°C. Capacitance drift or hysteresis for C0G (NP0) ceramics is negligible at less than  $\pm 0.05\%$  versus up to ±2% for films. Typical capacitance change with life is less than  $\pm$ 0.1% for COG (NP0), one-fifth that shown by most other dielectrics. C0G (NP0) formulations show no aging characteristics.

The C0G (NP0) formulation usually has a "Q" in excess of 1000 and shows little capacitance or "Q" changes with frequency. Their dielectric absorption is typically less than 0.6% which is similar to mica and most films.

#### **PART NUMBER (see page 2 for complete part number explanation)**





### <span id="page-5-0"></span>**Specifications and Test Methods**



### <span id="page-6-0"></span>**Capacitance Range**

### **PREFERRED SIZES ARE SHADED**



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### **Capacitance Range**







# <span id="page-8-0"></span>**RF/Microwave C0G (NP0) Capacitors**

### **Ultra Low ESR, "U" Series, C0G (NP0) Chip Capacitors**

### **GENERAL INFORMATION**

"U" Series capacitors are C0G (NP0) chip capacitors specially designed for "Ultra" low ESR for applications in the communications market. Max ESR and effective capacitance are met on each value producing lot to lot uniformity. Sizes available are EIA chip sizes 0603, 0805, and 1210.

#### **DIMENSIONS: inches (millimeters)**







**inches (mm)**



C

 $\overline{1}$ 

#### **HOW TO ORDER**



#### **ELECTRICAL CHARACTERISTICS**

#### **Capacitance Values and Tolerances:**

Size 0402 - 0.2 pF to 22 pF @ 1 MHz Size 0603 - 1.0 pF to 100 pF @ 1 MHz Size 0805 - 1.6 pF to 160 pF @ 1 MHz Size 1210 - 2.4 pF to 1000 pF @ 1 MHz

#### **Temperature Coefficient of Capacitance (TC):**

 $0\pm 30$  ppm/°C (-55° to +125°C)

#### **Insulation Resistance (IR):**

10<sup>12</sup> Ω min. @ 25°C and rated WVDC  $10^{11}$  Ω min. @ 125°C and rated WVDC

#### **Working Voltage (WVDC):**



#### **Dielectric Working Voltage (DWV):**

250% of rated WVDC

#### **Equivalent Series Resistance Typical (ESR):**

- 0402 See Performance Curve, page 9
- 0603 See Performance Curve, page 9<br>0805 See Performance Curve, page 9
	- See Performance Curve, page 9
- 1210 See Performance Curve, page 9

**Marking:** Laser marking EIA J marking standard (except 0603) (capacitance code and tolerance upon request).

#### **MILITARY SPECIFICATIONS**

Meets or exceeds the requirements of MIL-C-55681



# <span id="page-9-0"></span>**RF/Microwave C0G (NP0) Capacitors / WAX Ultra Low ESR, "U" Series, C0G (NP0) Chip Capacitors**

#### **CAPACITANCE RANGE**





### **ULTRA LOW ESR, "U" SERIES**







**TYPICAL ESR vs. FREQUENCY 0603 "U" SERIES**







**ESR Measured on the Boonton 34A**

**AVAK** Downloaded From [Oneyac.com](https://www.oneyac.com) **RF/Microwave C0G (NP0) Capacitors / AVAX** 

**Ultra Low ESR, "U" Series, C0G (NP0) Chip Capacitors**





## <span id="page-11-0"></span>**Designer Kits Communication Kits "U" Series**



### **"U" SERIES KITS**

Solder Plated, Nickel Barrier



**\* 150 Capacitors 10 each of 15 values.** 



**\*\* 240 Capacitors 10 each of 24 values.**

#### **0805 1210**



**\*\*\* 300 Capacitors 10 each of 30 values.** 

**†Tolerance – B = ±0.1pF C = ±0.25pF J = ±5%**

## <span id="page-12-0"></span>**X7R Dielectric General Specifications**





X7R formulations are called "temperature stable" ceramics and fall into EIA Class II materials. X7R is the most popular of these intermediate dielectric constant materials. Its temperature variation of capacitance is within  $±15%$  from -55°C to +125°C. This capacitance change is non-linear.

Capacitance for X7R varies under the influence of electrical operating conditions such as voltage and frequency.

X7R dielectric chip usage covers the broad spectrum of industrial applications where known changes in capacitance due to applied voltages are acceptable.

### **PART NUMBER (see page 2 for complete part number explanation)**



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### <span id="page-13-0"></span>**Specifications and Test Methods**



### <span id="page-14-0"></span>**Capacitance Range**







### **Capacitance Range**







# <span id="page-16-0"></span>**X7S Dielectric**

### **General Specifications**





#### **GENERAL DESCRIPTION**

X7S formulations are called "temperature stable" ceramics and fall into EIA Class II materials. X7S is the most popular of these intermediate dielectric constant materials. Its temperature variation of capacitance is within  $\pm 22\%$  from  $-55^{\circ}$ C to  $+125^{\circ}$ C. This capacitance change is non-linear.

Capacitance for X7S varies under the influence of electrical operating conditions such as voltage and frequency.

X7S dielectric chip usage covers the broad spectrum of industrial applications where known changes in capacitance due to applied voltages are acceptable.

#### **PART NUMBER (see page 2 for complete part number explanation)**



### **TYPICAL ELECTRICAL CHARACTERISTICS**



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# <span id="page-17-0"></span>**X7S Dielectric**

### **Specifications and Test Methods**





# <span id="page-18-0"></span>**X7S Dielectric**

### **Capacitance Range**





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### <span id="page-19-0"></span>**General Specifications**





### **GENERAL DESCRIPTION**

- General Purpose Dielectric for Ceramic Capacitors
- EIA Class II Dielectric
- Temperature variation of capacitance is within  $±15\%$ from  $-55^{\circ}$ C to  $+85^{\circ}$ C
- Well suited for decoupling and filtering applications
- Available in High Capacitance values (up to 100µF)

#### **PART NUMBER (see page 2 for complete part number explanation)**



### **TYPICAL ELECTRICAL CHARACTERISTICS**





### <span id="page-20-0"></span>**Specifications and Test Methods**







### <span id="page-21-0"></span>**Capacitance Range**





### **Capacitance Range**





AVX



## <span id="page-23-0"></span>**Y5V Dielectric General Specifications**





Y5V formulations are for general-purpose use in a limited temperature range. They have a wide temperature characteristic of +22% –82% capacitance change over the operating temperature range of –30°C to +85°C.

These characteristics make Y5V ideal for decoupling applications within limited temperature range.

### **PART NUMBER (see page 2 for complete part number explanation)**



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# <span id="page-24-0"></span>**Y5V Dielectric**

### **Specifications and Test Methods**







# <span id="page-25-0"></span>**Y5V Dielectric**



### **Capacitance Range**







### <span id="page-26-0"></span>**General Specifications**



AVX Corporation will support those customers for commercial and military Multilayer Ceramic Capacitors with a termination consisting of 5% minimum lead. This termination is indicated by the use of a "B" in the 12th position of the AVX Catalog Part Number. This fulfills AVX's commitment to providing a full range of products to our customers. AVX has provided in the following pages a full range of values that we are currently offering in this special "B" termination. Please contact the factory if you require additional information on our MLCC Tin/Lead Termination "B" products.

### **PART NUMBER (see page 2 for complete part number explanation)**



\*Contact factory

LD18 - 0612 LICC

### **ELECTRICAL GRAPHS**







<span id="page-27-0"></span>**Capacitance Range (NPO Dielectric)**







**Capacitance Range (NPO Dielectric)**







### **Capacitance Range (X7R Dielectric)**



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**Capacitance Range (X7R Dielectric)**







**Capacitance Range (X5R Dielectric)**

### **PREFERRED SIZES ARE SHADED**



**PAPER** EMBOSSED

# <span id="page-32-0"></span>**Automotive MLCC**

### **Automotive**

### **GENERAL DESCRIPTION**

AVX Corporation has supported the Automotive Industry requirements for Multilayer Ceramic Capacitors consistently for more than 10 years. Products have been developed and tested specifically for automotive applications and all manufacturing facilities are QS9000 and VDA 6.4 approved.

As part of our sustained investment in capacity and state of the art technology, we are now transitioning from the established Pd/Ag electrode system to a Base Metal Electrode system (BME).

AVX is using AECQ200 as the qualification vehicle for this transition. A detailed qualification package is available on request and contains results on a range of part numbers including:

- X7R dielectric components containing BME electrode and copper terminations with a Ni/Sn plated overcoat.
- X7R dielectric components BME electrode and soft terminations with a Ni/Sn plated overcoat.
- NP0 dielectric components containing Pd/Ag electrode and silver termination with a Ni/Sn plated overcoat.



AVX

#### **HOW TO ORDER**

 $200V = 2$ 



### **COMMERCIAL VS AUTOMOTIVE MLCC PROCESS COMPARISON**



**All Tests have Accept/Reject Criteria 0/1**



# **Automotive MLCC**

### **NP0/X7R Dielectric**



### **SOFT TERMINATION FEATURES**

a) Bend Test

The capacitor is soldered to the PC Board as shown:



Typical bend test results are shown below:



#### **NP0 DIELECTRIC**

**ELECTRODE AND TERMINATION OPTIONS**





*Figure 1 Termination Code T*

#### **X7R DIELECTRIC**

#### **X7R Dielectric PCB Application**



*Figure 2 Termination Code T*

**X7R Nickel Electrode Soft Termination PCB Application**



*Figure 3 Termination Code Z*

#### **Conductive Epoxy Termination Hybrid Application**



*Figure 4 Termination Code U*



b) Temperature Cycle testing "Soft Termination" has the ability to withstand at least 1000 cycles between –55°C and +125°C

# <span id="page-34-0"></span>**NP0 Automotive**

### **Capacitance Range (Ni Barrier Termination)**

AVAK





# **BME X7R Automotive**



### **Capacitance Range (Ni Barrier Termination)**






## **General Specifications**

## **GENERAL DESCRIPTION**

With increased requirements from the automotive industry for additional component robustness, AVX recognized the need to produce a MLCC with enhanced mechanical strength. It was noted that many components may be subject to severe flexing and vibration when used in various under the bonnet automotive applications.

To satisfy the requirement for enhanced mechanical strength, AVX had to find a way of ensuring electrical integrity is maintained whilst external forces are being applied to the component. It was found that the structure of the termination needed to be flexible and after much research and development, a "soft termination" was found. This soft termination is designed to enhance the mechanical flexure and temperature cycling performance of a standard ceramic capacitor with an X7R dielectric. **The industry standard for flexure is 2 mm minimum with Soft Termination. AVX guarantees a minimum flexure of 5 mm, without any internal cracks. Beyond 5mm generally the component will open. The industry standard for temperature cycling is 1000 cycles, AVX guarantees 3000 cycles.**

As well as for automotive applications the Soft Termination will provide Design Engineers with a satisfactory solution when designing PCB's which may be subject to high levels of board flexure.

## **PRODUCT ADVANTAGES**

- High mechanical performance able to withstand, 5mm bend test guaranteed.
- Open failure mode is apparent when products are overstressed by 5mm.
- Increased temperature cycling performance, 3000 cycles and beyond.
- Flexible termination system.
- Reduction in circuit board flex failures.
- Base metal electrode system.

 $2 = 200V$ 

• Automotive or commercial grade products available.

## **HOW TO ORDER**







## **APPLICATIONS**

### **High Flexure Stress Circuit Boards**

• e.g. Depanelization: Components near edges of board.

### **Variable Temperature Applications**

- Soft termination offers improved reliability performance in applications where there is temperature variation.
- e.g. All kind of engine sensors: Direct connection to battery rail.

### **Automotive Applications**

- Improved reliability.
- Excellent mechanical performance and thermo mechanical performance.

**2**

**A**

**Special Code** A = Std. Product

**Packaging**   $2 = 7"$  reel  $4 = 13"$  reel



## **Specifications and Test Methods**

## **AEC-Q200 Qualification:**

- Created by the Automotive Electronics Council
- Specification defining stress test qualification for passive components



Key tests used to compare soft termination to AEC-Q200 qualification:

- Bend Test
- Temperature Cycle Test

## **BOARD BEND TEST RESULTS**

AEC-Q200 Vrs AVX Soft Termination Bend Test









## **TABLE SUMMARY**

Typical bend test results are shown below:



## **TEMPERATURE CYCLE TEST PROCEDURE**

## **Test Procedure as per AEC-Q200:**

The test is conducted to determine the resistance of the component when it is exposed to extremes of alternating high and low temperatures.

- Sample lot size quantity 77 pieces
- TC chamber cycle from -55ºC to +125ºC for 1000 cycles
- Interim electrical measurements at 250, 500, 1000 cycles
- Measure parameter capacitance dissipation factor, insulation resistance



## **PERFORMANCE TESTING BOARD BEND TEST PROCEDURE**

According to AEC-Q200

Test Procedure as per AEC-Q200: Sample size: 20 components

Span: 90mm Minimum deflection spec: 2 mm

- Components soldered onto FR4 PCB (Figure 1)
- Board connected electrically to the test equipment (Figure 2)

BEND TESTPLATE

**Fig 1 - PCB layout with electrical connections**



**Fig 2 - Board Bend test equipment**

## **AVX ENHANCED SOFT TERMINATION BEND TEST PROCEDURE**

CONTROL PANEL

CONNECTOR

## **Bend Test**

The capacitor is soldered to the printed circuit board as shown and is bent up to 10mm at 1mm per second:



- The board is placed on 2 supports 90mm apart (capacitor side down)
- The row of capacitors is aligned with the load stressing knife



- The load is applied and the deflection where the part starts to crack is recorded (Note: Equipment detects the start of the crack using a highly sensitive current detection circuit)
- The maximum deflection capability is 10mm





## **Specifications and Test Methods**

## **BEYOND 1000 CYCLES: TEMPERATURE CYCLE TEST RESULTS**



## **Soft Term - No Defects up to 3000 cycles**

**SOFT TERMINATION TEST SUMMARY**

- Qualified product by using the AEC-Q200 test/specification with the exception of using AVX 3000 temperature cycles (up to +150°C bend test guaranteed greater than 5mm).
- Soft Termination provides improved performance compared to standard termination systems.

**AEC-Q200 specification states 1000 cycles compared to AVX 3000 temperature cycles.**

- Board bend test improvement by a factor of 2 to 4 times.
- Temperature Cycling:
	- 0% Failure up to 3000 cycles
	- No ESR change up to 3000 cycles



## **WITHOUT SOFT TERMINATION WITH SOFT TERMINATION**



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## **X7R Dielectric Capacitance Range**





**= Range extension parts**

# **Capacitor Array**

## **Capacitor Array (IPC)**



## **BENEFITS OF USING CAPACITOR ARRAYS**

AVX capacitor arrays offer designers the opportunity to lower placement costs, increase assembly line output through lower component count per board and to reduce real estate requirements.

### **Reduced Costs**

Placement costs are greatly reduced by effectively placing one device instead of four or two. This results in increased throughput and translates into savings on machine time. Inventory levels are lowered and further savings are made on solder materials, etc.

### **Space Saving**

Space savings can be quite dramatic when compared to the use of discrete chip capacitors. As an example, the 0508 4-element array offers a space reduction of >40% vs. 4 x 0402 discrete capacitors and of >70% vs. 4 x 0603 discrete capacitors. (This calculation is dependent on the spacing of the discrete components.)

### **Increased Throughput**

Assuming that there are 220 passive components placed in a mobile phone:

A reduction in the passive count to 200 (by replacing discrete components with arrays) results in an increase in throughput of approximately 9%.

A reduction of 40 placements increases throughput by 18%.

For high volume users of cap arrays using the very latest placement equipment capable of placing 10 components per second, the increase in throughput can be very significant and can have the overall effect of reducing the number of placement machines required to mount components:

If 120 million 2-element arrays or 40 million 4-element arrays were placed in a year, the requirement for placement equipment would be reduced by one machine.

During a 20Hr operational day a machine places 720K components. Over a working year of 167 days the machine can place approximately 120 million. If 2-element arrays are mounted instead of discrete components, then the number of placements is reduced by a factor of two and in the scenario where 120 million 2-element arrays are placed there is a saving of one pick and place machine.

Smaller volume users can also benefit from replacing discrete components with arrays. The total number of placements is reduced thus creating spare capacity on placement machines. This in turn generates the opportunity to increase overall production output without further investment in new equipment.

### **W2A (0508) Capacitor Arrays**



The 0508 4-element capacitor array gives a PCB space saving of over 40% vs four 0402 discretes and over 70% vs four 0603 discrete capacitors.

## **W3A (0612) Capacitor Arrays**



The 0612 4-element capacitor array gives a PCB space saving of over 50% vs four 0603 discretes and over 70% vs four 0805 discrete capacitors.



# **Capacitor Array**







# **Capacitor Array Multi-Value Capacitor Array (IPC)**



## **GENERAL DESCRIPTION**

A recent addition to the array product range is the Multi-Value Capacitor Array. These devices combine two different capacitance values in standard 'Cap Array' packages and are available with a maximum ratio between the two capacitance values of 100:1. The multi-value array is currently available in the 0405 and 0508 2-element styles and also in the 0612 4-element style.

Whereas to date AVX capacitor arrays have been suited to applications where multiple capacitors of the same value are used, the multi-value array introduces a new flexibility to the range. The multi-value array can replace discrete capacitors of different values and can be used for broadband decoupling applications. The 0508 x 2 element multi-value array would be particularly recommended in this application. Another application is filtering the 900/1800 or 1900MHz noise in mobile phones. The 0405 2-element, low capacitance value NP0, (C0G) device would be suited to this application, in view of the space saving requirements of mobile phone manufacturers.

## **ADVANTAGES OF THE MULTI-VALUE CAPACITOR ARRAYS**

### **Enhanced Performance Due to Reduced Parasitic Inductance**

When connected in parallel, not only do discrete capacitors of different values give the desired self-resonance, but an additional unwanted parallel resonance also results. This parallel resonance is induced between each capacitor's self-resonant frequencies and produces a peak in impedance response. For decoupling and bypassing applications this peak will result in a frequency band of reduced decoupling and in filtering applications reduced attenuation.

The multi-value capacitor array, combining capacitors in one unit, virtually eliminates the problematic parallel resonance, by minimizing parasitic inductance between the capacitors, thus enhancing the broadband decoupling/filtering performance of the part.

### **Reduced ESR**

An advantage of connecting two capacitors in parallel is a significant reduction in ESR. However, as stated above, using discrete components brings with it the unwanted side effect of parallel resonance. The multi-value cap array is an excellent alternative as not only does it perform the same function as parallel capacitors but also it reduces the uncertainty of the frequency response.

## **HOW TO ORDER**





- Max. ratio between the two cap values is 1:100.
- The voltage of the higher capacitance value dictates the voltage of the multi-value part.
- Only combinations of values within a specific dielectric range are possible.

## **IMPEDANCE VS FREQUENCY**







## **PART & PAD LAYOUT DIMENSIONS** millimeters (inches)





## **PART DIMENSIONS**

## **0405 - 2 Element**







## **0508 - 4 Element**



## **0612 - 4 Element**



### **PAD LAYOUT DIMENSIONS 0405 - 2 Element**





### **0508 - 4 Element**



## **0612 - 4 Element**





## **Introduction**

As switching speeds increase and pulse rise times decrease the need to reduce inductance becomes a serious limitation for improved system performance. Even the decoupling capacitors, that act as a local energy source, can generate unacceptable voltage spikes:  $V = L$  (di/dt). Thus, in high speed circuits, where di/dt can be quite large, the size of the voltage spike can only be reduced by reducing L.

Figure 1 displays the evolution of ceramic capacitor toward lower inductance designs over the last few years. AVX has been at the forefront in the design and manufacture of these newer more effective capacitors.



*Figure 1. The evolution of Low Inductance Capacitors at AVX (values given for a 100 nF capacitor of each style)*

## **LOW INDUCTANCE CHIP CAPACITORS**

The total inductance of a chip capacitor is determined both by its length to width ratio and by the mutual inductance coupling between its electrodes. Thus a 1210 chip size has lower inductance than a 1206 chip. This design improvement is the basis of AVX's low inductance chip capacitors, LI Caps, where the electrodes are terminated on the long side of the chip instead of the short side. The 1206 becomes an 0612 as demonstrated in Figure 2. In the same manner, an 0805 becomes an 0508 and 0603 becomes an 0306. This results in a reduction in inductance from around 1200 pH for conventional MLC chips to below 200 pH for Low Inductance Chip Capacitors. Standard designs and performance of these LI Caps are given on pages 46 and 47.



*Figure 2. Change in aspect ratio: 1206 vs. 0612*

## **INTERDIGITATED CAPACITORS**

Multiple terminations of a capacitor will also help in reducing the parasitic inductance of the device. The IDC is such a device. By terminating one capacitor with 8 connections the ESL can be reduced even further. The measured inductance of the 0612 IDC is 60 pH, while the 0508 comes in around 50 pH. These FR4 mountable devices allow for even higher clock speeds in a digital decoupling scheme. Design and product offerings are shown on pages 48 and 49.



## **LOW INDUCTANCE CHIP ARRAYS (LICA®)**

Further reduction in inductance can be achieved by designing alternative current paths to minimize the mutual inductance factor of the electrodes (Figure 3). This is achieved by AVX's LICA® product which was the result of a joint development between AVX and IBM. As shown in Figure 4, the charging current flowing out of the positive plate returns in the opposite direction along adjacent negative plates. This minimizes the mutual inductance.

The very low inductance of the LICA capacitor stems from the short aspect ratio of the electrodes, the arrangement of the tabs so as to cancel inductance, and the vertical aspect of the electrodes to the mounting surface.



*Figure 3. Net Inductance from design. In the standard Multilayer capacitor, the charge currents entering and leaving the capacitor create complementary flux fields, so the net inductance is greater. On the right, however, if the design permits the currents to be opposed, there is a net cancellation, and the inductance is much lower.*

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## **Introduction**



*Figure 4. LICA's Electrode/Termination Construction. The current path is minimized – this reduces self-inductance. Current flowing out of the positive plate, returns in the opposite direction along the adjacent negative plate – this reduces the mutual inductance.*

Also the effective current path length is minimized because the current does not have to travel the entire length of both electrodes to complete the circuit. This reduces the self inductance of the electrodes. The self inductance is also minimized by the fact that the charging current is supplied by both sets of terminals reducing the path length even further!

The inductance of this arrangement is less than 30 pH, causing the self-resonance to be above 100 MHz for the same popular 100 nF capacitance. Parts available in the LICA design are shown on pages 50 and 51.

Figure 5 compares the self resonant frequencies of various capacitor designs versus capacitance values. The approximate inductance of each style is also shown.

*Active development continues on low inductance capacitors. C4 termination with low temperature solder is now available for plastic packages. Consult AVX for details.*



*Figure 5. Self Resonant Frequency vs. Capacitance and Capacitor Design*

![](_page_45_Picture_11.jpeg)

## **0612/0508/0306 LICC (Low Inductance Chip Capacitors)**

## **GENERAL DESCRIPTION**

The total inductance of a chip capacitor is determined both by its length to width ratio and by the mutual inductance coupling between its electrodes.

Thus a 1210 chip size has a lower inductance than a 1206 chip. This design improvement is the basis of AVX's Low Inductance Chip Capacitors (LICC), where the electrodes are terminated on the long side of the chip instead of the short side. The 1206 becomes an 0612, in the same manner, an 0805 becomes an 0508, an 0603 becomes an 0306. This results in a reduction in inductance from the 1nH range found in normal chip capacitors to less than 0.2nH for LICCs. Their low profile is also ideal for surface mounting (both on the PCB and on IC package) or inside cavity mounting on the IC itself.

AVX

![](_page_46_Picture_6.jpeg)

## **HOW TO ORDER**

![](_page_46_Figure_8.jpeg)

## **PERFORMANCE CHARACTERISTICS**

![](_page_46_Picture_373.jpeg)

## **TYPICAL INDUCTANCE**

![](_page_46_Picture_374.jpeg)

\*Note: See Range Chart for Codes

## **TYPICAL IMPEDANCE CHARACTERISTICS**

![](_page_46_Figure_15.jpeg)

![](_page_46_Figure_16.jpeg)

![](_page_46_Picture_17.jpeg)

**0612/0508/0306 LICC (Low Inductance Chip Capacitors)**

![](_page_47_Figure_2.jpeg)

**0508 Code Thickness S** 0.56 (0.022) **V** 0.76 (0.030) **A** 1.02 (0.040)

**0612 Code Thickness S** 0.56 (0.022) **V** 0.76 (0.030) **W** 1.02 (0.040) **A** 1.27 (0.050)

**0306 Code Thickness A** 0.61 (0.024)

## **PHYSICAL DIMENSIONS AND PAD LAYOUT**

![](_page_47_Figure_4.jpeg)

AVX

## **PHYSICAL CHIP DIMENSIONS mm (in)**

L | W | t **0612** 1.60 ± 0.25 3.20 ± 0.25 0.13 min.<br>  $(0.063 \pm 0.010)$   $(0.126 \pm 0.010)$   $(0.005 \text{ min.})$  $(0.126 \pm 0.010)$ **0508**  $\begin{bmatrix} 1.27 \pm 0.25 \\ 0.050 \pm 0.010 \end{bmatrix}$   $\begin{bmatrix} 2.00 \pm 0.25 \\ 0.080 \pm 0.010 \end{bmatrix}$   $\begin{bmatrix} 0.13 \text{ min.} \\ 0.005 \text{ min.} \end{bmatrix}$  $(0.050 \pm 0.010)$   $(0.080 \pm 0.010)$   $(0.005 \text{ min.})$ **0306**  $\begin{bmatrix} 0.81 \pm 0.15 \\ 0.032 + 0.006 \end{bmatrix}$   $\begin{bmatrix} 1.60 \pm 0.15 \\ 0.063 + 0.006 \end{bmatrix}$   $\begin{bmatrix} 0.13 \text{ min.} \\ 0.005 \text{ min.} \end{bmatrix}$  $(0.032 \pm 0.006)$   $(0.063 \pm 0.006)$   $(0.005 \text{ min.})$ 

T - See Range Chart for Thickness and Codes

## **PAD LAYOUT DIMENSIONS mm (in)**

![](_page_47_Picture_302.jpeg)

![](_page_47_Figure_10.jpeg)

![](_page_47_Picture_11.jpeg)

## **0612/0508 IDC (InterDigitated Capacitors)**

![](_page_48_Picture_2.jpeg)

## **GENERAL DESCRIPTION**

- Very low equivalent series inductance (ESL), surface mountable, high speed decoupling capacitor in 0612 and 0508 case size.
- Measured inductances of 60 pH (for 0612) and 50 pH (for 0508) are the lowest in the FR4 mountable device family. Now use 10T devices with inductances of 45 pH (for 0612) and 35 pH (for 0508).
- Opposing current flow creates opposing magnetic fields. This causes the fields to cancel, effectively reducing the equivalent series inductance.
- Perfect solution for decoupling high speed microprocessors by allowing the engineers to lower the power delivery inductance of the entire system through the use of eight vias.
- Overall reduction in decoupling components due to very low series inductance and high capacitance.

![](_page_48_Picture_9.jpeg)

+ – + –

## **HOW TO ORDER**

![](_page_48_Figure_11.jpeg)

## **PERFORMANCE CHARACTERISTICS**

![](_page_48_Picture_395.jpeg)

![](_page_48_Picture_396.jpeg)

## **TYPICAL ESL AND IMPEDANCE**

![](_page_48_Picture_397.jpeg)

![](_page_48_Figure_17.jpeg)

![](_page_48_Picture_18.jpeg)

## **0612/0508 IDC (InterDigitated Capacitors)**

![](_page_49_Picture_253.jpeg)

Consult factory for additional requirements

AVX

![](_page_49_Figure_4.jpeg)

## **PHYSICAL DIMENSIONS AND PAD LAYOUT**

![](_page_49_Figure_6.jpeg)

## **PHYSICAL CHIP DIMENSIONS millimeters (inches)**

## **0612**

![](_page_49_Picture_254.jpeg)

## **0508**

![](_page_49_Picture_255.jpeg)

![](_page_49_Picture_12.jpeg)

## **0612**

![](_page_49_Picture_256.jpeg)

## **0508**

![](_page_49_Picture_257.jpeg)

![](_page_49_Picture_17.jpeg)

## **LICA® (Low Inductance Decoupling Capacitor Arrays)**

![](_page_50_Picture_2.jpeg)

![](_page_50_Picture_3.jpeg)

LICA® arrays utilize up to four separate capacitor sections in one ceramic body (see Configurations and Capacitance Options). These designs exhibit a number of technical advancements:

Low Inductance features–

Low resistance platinum electrodes in a low aspect ratio pattern Double electrode pickup and perpendicular current paths C4 "flip-chip" technology for minimal interconnect inductance

## **HOW TO ORDER**

![](_page_50_Picture_529.jpeg)

## **C4 AND PAD DIMENSIONS**

![](_page_50_Figure_10.jpeg)

7 1.600mm 1.850mm 1.600mm

## **TERMINATION OPTIONS C4 SOLDER (97% Pb/3% Sn) BALLS**

![](_page_50_Picture_12.jpeg)

## **TERMINATION OPTION P OR N**

![](_page_50_Picture_14.jpeg)

**AVAK** Downloaded From [Oneyac.com](https://www.oneyac.com)

**LICA® (Low Inductance Decoupling Capacitor Arrays)**

## **LICA® TYPICAL PERFORMANCE CURVES**

![](_page_51_Figure_3.jpeg)

*Effect of Bias Voltage and Temperature on a 130 nF LICA® (T55T)*

![](_page_51_Figure_5.jpeg)

AVX

## **LICA VALID PART NUMBER LIST CONFIGURATION**

![](_page_51_Picture_462.jpeg)

![](_page_51_Figure_8.jpeg)

![](_page_51_Figure_9.jpeg)

## **WAFFLE PACK OPTIONS FOR LICA®**

![](_page_51_Figure_11.jpeg)

Note: Standard configuration is Termination side down

## **LICA® PACKAGING SCHEME "M" AND "R"**

**8mm conductive plastic tape on reel: "M"=7" reel max. qty. 3,000, "R"=13" reel max. qty. 8,000** 

![](_page_51_Figure_15.jpeg)

Downloaded From **[Oneyac.com](https://www.oneyac.com)** 

# **High Voltage MLC Chips**

## **For 600V to 5000V Application**

![](_page_52_Picture_2.jpeg)

![](_page_52_Picture_3.jpeg)

High value, low leakage and small size are difficult parameters to obtain in capacitors for high voltage systems. AVX special high voltage MLC chips capacitors meet these performance characteristics and are designed for applications such as snubbers in high frequency power converters, resonators in SMPS, and high voltage coupling/DC blocking. These high voltage chip designs exhibit low ESRs at high frequencies.

Larger physical sizes than normally encountered chips are used to make high voltage chips. These larger sizes require that special precautions be taken in applying these chips in surface mount assemblies. This is due to differences in the coefficient of thermal expansion (CTE) between the substrate materials and chip capacitors. Apply heat at less than 4°C per second during the preheat. The preheat temperature must be within 50°C of the peak temperature reached by the ceramic bodies through the soldering process. Chips 1808 and larger to use reflow soldering only.

Capacitors with X7R Dielectrics are not intended for AC line filtering applications. Contact plant for recommendations.

Capacitors may require protective surface coating to prevent external arcing.

## **HOW TO ORDER**

![](_page_52_Picture_200.jpeg)

![](_page_52_Picture_10.jpeg)

![](_page_52_Picture_201.jpeg)

\*Reflow Soldering Only

![](_page_52_Picture_14.jpeg)

# **High Voltage MLC Chips**

![](_page_53_Picture_1.jpeg)

## **For 600V to 5000V Applications**

## **C0G Dielectric**

## **Performance Characteristics**

![](_page_53_Picture_288.jpeg)

## **HIGH VOLTAGE C0G CAPACITANCE VALUES**

![](_page_53_Picture_289.jpeg)

## **X7R Dielectric**

## **Performance Characteristics**

![](_page_53_Picture_290.jpeg)

## **HIGH VOLTAGE X7R MAXIMUM CAPACITANCE VALUES**

![](_page_53_Picture_291.jpeg)

![](_page_53_Picture_13.jpeg)

## **MIL-PRF-55681/Chips Part Number Example CDR01 thru CDR06**

![](_page_54_Picture_1.jpeg)

![](_page_54_Figure_2.jpeg)

## **MILITARY DESIGNATION PER MIL-PRF-55681**

![](_page_54_Figure_4.jpeg)

**MIL Style:** CDR01, CDR02, CDR03, CDR04, CDR05, CDR06

### **Voltage Temperature Limits:**

- $BP = 0 \pm 30$  ppm/°C without voltage;  $0 \pm 30$  ppm/°C with rated voltage from -55°C to +125°C
- $BX = \pm 15\%$  without voltage; +15 –25% with rated voltage from -55°C to +125°C

**Capacitance:** Two digit figures followed by multiplier (number of zeros to be added) e.g.,  $101 = 100$  pF

**Rated Voltage:** A = 50V, B = 100V

**Capacitance Tolerance:**  $J \pm 5\%$ ,  $K \pm 10\%$ ,  $M \pm 20\%$ 

### **Termination Finish:**

- $N =$  Silver Nickel Gold
- 
- M = Palladium Silver U = Base Metallization/Barrier<br>N = Silver Nickel Gold Metal/Solder Coated\*
- S = Solder-coated W = Base Metallization/Barrier Metal/Tinned (Tin or Tin/ Lead Alloy)

\*Solder shall have a melting point of 200°C or less.

**Failure Rate Level:** M = 1.0%, P = .1%, R = .01%,  $S = .001\%$ 

**Packaging:** Bulk is standard packaging. Tape and reel per RS481 is available upon request.

## **Per** AVX Length (L) Width (W) Thickness (T) D Termination Band (t) MIL-PRF-55681 Style Length (L) Width (W) Max. Min. Max. Min. Max. Min. Max. Min. CDR01 0805 .080 ± .015 .050 ± .015 .055 .020 — .030 — .010

CDR02 1805 .180 ± .015 .050 ± .015 .055 .020 — — .030 .010 CDR03 1808 .180 ± .015 .080 ± .018 .080 .020 — — .030 .010 CDR04 1812 .180 ± .015 .125 ± .015 .080 .020 — — .030 .010

 $\texttt{CDRO5} \qquad \left| \begin{array}{ccc} 1825 \ 1825 \end{array} \right| \; .080 \; .020 \; .030 \; .020 \; \left| \begin{array}{ccc} \texttt{0.00} \end{array} \right| \; .030 \; .010$ 

CDR06 2225 .225 ± .020 .250 ± .020 .080 .020 — — .030 .010

**CROSS REFERENCE: AVX/MIL-PRF-55681/CDR01 THRU CDR06\***

\*For CDR11, 12, 13, and 14 see AVX Microwave Chip Capacitor Catalog

## **MIL-PRF-55681/Chips Military Part Number Identification CDR01 thru CDR06**

![](_page_55_Picture_1.jpeg)

![](_page_55_Picture_363.jpeg)

- Add appropriate termination finish

Capacitance Tolerance

![](_page_55_Picture_364.jpeg)

CDR06BX474A---

CDR06BP682B--- 6800 J,K BP 100 CDR06BP822B--- 8200 J,K BP 100 CDR06BP103B--- 10,000 J,K BP 100<br>CDR06BX394A--- 390,000 K BX 50<br>CDR06BX474A--- 470,000 K,M BX 50

CDR06BX394A--- 390,000 K BX<br>CDR06BX474A--- 470,000 KM BX

Add appropriate failure rate Add appropriate termination finish

Capacitance Tolerance

## **MIL-PRF-55681/Chips Part Number Example CDR31 thru CDR35**

![](_page_56_Picture_1.jpeg)

![](_page_56_Figure_2.jpeg)

## **MILITARY DESIGNATION PER MIL-PRF-55681**

![](_page_56_Picture_242.jpeg)

### **MIL Style:** CDR31, CDR32, CDR33, CDR34, CDR35

### **Voltage Temperature Limits:**

- $BP = 0 \pm 30$  ppm/°C without voltage;  $0 \pm 30$  ppm/°C with rated voltage from -55°C to +125°C
- $BX = ±15%$  without voltage;  $+15 -25%$  with rated voltage from  $-55^{\circ}$ C to  $+125^{\circ}$ C

**Capacitance:** Two digit figures followed by multiplier (number of zeros to be added) e.g.,  $101 = 100$  pF

**Rated Voltage:** A = 50V, B = 100V

**Capacitance Tolerance:**  $C \pm .25$  pF,  $D \pm .5$  pF,  $F \pm 1\%$  $J \pm 5\%$ , K  $\pm$  10%, M  $\pm$  20%

### **Termination Finish:**

- 
- $N =$  Silver Nickel Gold
- 
- $M =$  Palladium Silver  $U =$  Base Metallization/Barrier  $N =$  Silver Nickel Gold Metal/Solder Coated\*
- S = Solder-coated W = Base Metallization/Barrier
	- Metal/Tinned (Tin or Tin/ Lead Alloy)

\*Solder shall have a melting point of 200°C or less.

**Failure Rate Level:** M = 1.0%, P = .1%, R = .01%,  $S = .001%$ 

**Packaging:** Bulk is standard packaging. Tape and reel per RS481 is available upon request.

## **CROSS REFERENCE: AVX/MIL-PRF-55681/CDR31 THRU CDR35**

![](_page_56_Picture_243.jpeg)

# **MIL-PRF-55681/Chips**

![](_page_57_Picture_1.jpeg)

## **Military Part Number Identification CDR31**

![](_page_57_Picture_354.jpeg)

## **CDR5** FR/84/7

Add appropriate failure rate

Add appropriate termination finish

Capacitance Tolerance

**1**/ The complete part number will include additional symbols to indicate capacitance tolerance, termination and failure rate level.

Capacitance Tolerance

![](_page_57_Picture_9.jpeg)

# **MIL-PRF-55681/Chips**

Add appropriate termination finish

Capacitance Tolerance

![](_page_58_Picture_1.jpeg)

**Rated temperature WVDC** 

**Designation 1**/ **in pF tolerance temperature limits**

## **Military Part Number Identification CDR32**

![](_page_58_Picture_373.jpeg)

Add appropriate failure rate

Add appropriate termination finish

Capacitance Tolerance

**1**/ The complete part number will include additional symbols to indicate capacitance tolerance, termination and failure rate level.

![](_page_58_Picture_9.jpeg)

Downloaded From **[Oneyac.com](https://www.oneyac.com)** 

# **MIL-PRF-55681/Chips Military Part Number Identification CDR33/34/35**

![](_page_59_Picture_1.jpeg)

# **CDR33/34/35 to MIL-PRF-55681/9/10/11**

![](_page_59_Picture_330.jpeg)

![](_page_59_Picture_331.jpeg)

Add appropriate termination finish

Capacitance Tolerance

![](_page_59_Picture_332.jpeg)

Add appropriate failure rate

Add appropriate termination finish

Capacitance Tolerance

**1**/ The complete part number will include additional symbols to indicate capacitance tolerance, termination and failure rate level.

![](_page_59_Picture_12.jpeg)

# **Packaging of Chip Components**

![](_page_60_Picture_1.jpeg)

## **Automatic Insertion Packaging**

## **TAPE & REEL QUANTITIES**

All tape and reel specifications are in compliance with RS481.

![](_page_60_Picture_201.jpeg)

## **REEL DIMENSIONS**

![](_page_60_Figure_7.jpeg)

![](_page_60_Picture_202.jpeg)

Metric dimensions will govern.

English measurements rounded and for reference only.

(1) For tape sizes 16mm and 24mm (used with chip size 3640) consult EIA RS-481 latest revision.

![](_page_60_Picture_12.jpeg)

# **Embossed Carrier Configuration**

![](_page_61_Picture_1.jpeg)

## **8 & 12mm Tape Only**

![](_page_61_Figure_3.jpeg)

## **Chip Orientation**

![](_page_61_Picture_5.jpeg)

## **8 & 12mm Embossed Tape Metric Dimensions Will Govern**

## **CONSTANT DIMENSIONS**

![](_page_61_Picture_353.jpeg)

## **VARIABLE DIMENSIONS**

![](_page_61_Picture_354.jpeg)

### **NOTES:**

 $20<sup>c</sup>$ 

1. The cavity defined by  $A_0$ ,  $B_0$ , and  $K_0$  shall be configured to provide the following:

Surround the component with sufficient clearance such that:

a) the component does not protrude beyond the sealing plane of the cover tape. b) the component can be removed from the cavity in a vertical direction without mechanical restriction, after the cover tape has been removed.

c) rotation of the component is limited to 20º maximum (see Sketches D & E). d) lateral movement of the component is restricted to 0.5mm maximum (see Sketch F). 2. Tape with or without components shall pass around radius "R" without damage.

3. Bar code labeling (if required) shall be on the side of the reel opposite the round sprocket holes. Refer to EIA-556.

4. B<sub>1</sub> dimension is a reference dimension for tape feeder clearance only

5. If  $P_1 = 2.0$ mm, the tape may not properly index in all tape feeders.

![](_page_61_Figure_20.jpeg)

![](_page_61_Figure_21.jpeg)

# **Paper Carrier Configuration**

![](_page_62_Picture_1.jpeg)

## **8 & 12mm Tape Only**

![](_page_62_Figure_3.jpeg)

## **8 & 12mm Paper Tape Metric Dimensions Will Govern**

## **CONSTANT DIMENSIONS**

![](_page_62_Picture_354.jpeg)

## **VARIABLE DIMENSIONS**

![](_page_62_Picture_355.jpeg)

holes. Refer to EIA-556.

### **NOTES:**

- 1. The cavity defined by A<sub>0</sub>, B<sub>0</sub>, and T shall be configured to provide sufficient clearance surrounding the component so that:
	- a) the component does not protrude beyond either surface of the carrier tape; b) the component can be removed from the cavity in a vertical direction without
	- mechanical restriction after the top cover tape has been removed; c) rotation of the component is limited to 20º maximum (see Sketches A & B);
	- d) lateral movement of the component is restricted to 0.5mm maximum (see Sketch C).

![](_page_62_Figure_14.jpeg)

## 0.50mm (0.020) Maximum 0.50mm (0.020) Maximum **Top View, Sketch "C"** Component Lateral

## **Bar Code Labeling Standard**

AVX bar code labeling is available and follows latest version of EIA-556

![](_page_62_Picture_18.jpeg)

2. Tape with or without components shall pass around radius "R" without damage. 3. Bar code labeling (if required) shall be on the side of the reel opposite the sprocket

4. If  $P_1 = 2.0$ mm, the tape may not properly index in all tape feeders.

# **Bulk Case Packaging**

![](_page_63_Picture_1.jpeg)

## **BENEFITS BULK FEEDER**

- Easier handling
- Smaller packaging volume (1/20 of T/R packaging)
- Easier inventory control
- Flexibility
- Recyclable

## **CASE DIMENSIONS**

![](_page_63_Figure_9.jpeg)

![](_page_63_Figure_10.jpeg)

## **CASE QUANTITIES**

![](_page_63_Picture_117.jpeg)

# **Basic Capacitor Formulas**

![](_page_64_Picture_1.jpeg)

**I. Capacitance (farads)**

English:  $C = \frac{.224 \text{ K A}}{}$  $T_{\text{D}}$ Metric:  $C = \frac{.0884 \text{ K A}}{}$  $T_{\rm o}$ 

- **II. Energy stored in capacitors (Joules, watt sec)**  $E = \frac{1}{2}CV^2$
- **III. Linear charge of a capacitor (Amperes)**

$$
I = C \frac{dV}{dt}
$$

- **IV. Total Impedance of a capacitor (ohms)**  $Z = \sqrt{R_s^2 + (X_C - X_L)^2}$
- **V. Capacitive Reactance (ohms)**

$$
x_C = \frac{1}{2 \pi fC}
$$

- **VI. Inductive Reactance (ohms)**  $x_L = 2 \pi fL$
- **VII. Phase Angles:**

Ideal Capacitors: Current leads voltage 90° Ideal Inductors: Current lags voltage 90° Ideal Resistors: Current in phase with voltage

### **VIII. Dissipation Factor (%)**

D.F.= tan 
$$
\delta
$$
 (loss angle) =  $\frac{E.S.R.}{X_C}$  = (2  $\pi$ fC) (E.S.R.)

**IX. Power Factor (%)** P.F. = Sine  $\delta$  (loss angle) = Cos  $\phi$  (phase angle) P.F. = (when less than 10%) = DF

**X. Quality Factor (dimensionless)**

$$
Q = \text{Cotan } \delta \text{ (loss angle)} = \frac{1}{D.F.}
$$

## **METRIC PREFIXES SYMBOLS**

- **XI. Equivalent Series Resistance (ohms)** E.S.R. =  $(D.F.)$  (Xc) =  $(D.F.)$  / (2  $\pi$  fC)
- **XII. Power Loss (watts)** Power Loss =  $(2 \pi fCV^2)(D.F.)$

**XIII. KVA (Kilowatts)** KVA =  $2 \pi$  fCV<sup>2</sup> x 10<sup>-3</sup>

**XIV. Temperature Characteristic (ppm/°C)**

T.C. = 
$$
\frac{Ct - C_{25}}{C_{25} (T_t - 25)} \times 10^6
$$

- **XV. Cap Drift (%)** C.D. =  $\frac{C_1 - C_2}{C_1}$  x 100
- **XVI. Reliability of Ceramic Capacitors**  $L_o = \left(\frac{V_t}{V_o}\right)$  X  $\left(\frac{T_t}{T_o}\right)$  Y
- **XVII. Capacitors in Series (current the same)**

Any Number: 
$$
\frac{1}{C_T} = \frac{1}{C_1} + \frac{1}{C_2} - \frac{1}{C_N}
$$
  
Two:  $C_T = \frac{C_1 C_2}{C_1 + C_2}$ 

**XVIII. Capacitors in Parallel (voltage the same)**  $C_T = C_1 + C_2 - \cdots + C_N$ 

## **XIX. Aging Rate**

A.R. = % $\Delta$  C/decade of time

**XX. Decibels** db = 20  $\log \frac{V_1}{V_2}$ 

![](_page_64_Picture_450.jpeg)

![](_page_64_Picture_33.jpeg)

![](_page_65_Picture_1.jpeg)

**Basic Construction - A multilayer ceramic (MLC) capaci**tor is a monolithic block of ceramic containing two sets of offset, interleaved planar electrodes that extend to two opposite surfaces of the ceramic dielectric. This simple structure requires a considerable amount of sophistication, both in material and manufacture, to produce it in the quality and quantities needed in today's electronic equipment.

![](_page_65_Figure_4.jpeg)

**Formulations –** Multilayer ceramic capacitors are available in both Class 1 and Class 2 formulations. Temperature compensating formulation are Class 1 and temperature stable and general application formulations are classified as Class 2.

**Class 1 –** Class 1 capacitors or temperature compensating capacitors are usually made from mixtures of titanates where barium titanate is normally not a major part of the mix. They have predictable temperature coefficients and in general, do not have an aging characteristic. Thus they are the most stable capacitor available. The most popular Class 1 multilayer ceramic capacitors are C0G (NP0) temperature compensating capacitors (negative-positive 0 ppm/ $^{\circ}$ C).

**Class 2 –** EIA Class 2 capacitors typically are based on the chemistry of barium titanate and provide a wide range of capacitance values and temperature stability. The most commonly used Class 2 dielectrics are X7R and Y5V. The X7R provides intermediate capacitance values which vary only  $\pm$ 15% over the temperature range of -55°C to 125°C. It finds applications where stability over a wide temperature range is required.

The Y5V provides the highest capacitance values and is used in applications where limited temperature changes are expected. The capacitance value for Y5V can vary from 22% to -82% over the -30°C to 85°C temperature range.

All Class 2 capacitors vary in capacitance value under the influence of temperature, operating voltage (both AC and DC), and frequency. For additional information on performance changes with operating conditions, consult AVX's software, SpiCap.

![](_page_66_Picture_1.jpeg)

### **Table 1: EIA and MIL Temperature Stable and General Application Codes**

![](_page_66_Picture_334.jpeg)

EXAMPLE – A capacitor is desired with the capacitance value at 25°C to increase no more than 7.5% or decrease no more than 7.5% from -30°C to +85°C. EIA Code will be Y5F.

![](_page_66_Picture_335.jpeg)

In specifying capacitance change with temperature for Class 2 materials, EIA expresses the capacitance change over an operating temperature range by a 3 symbol code. The first symbol represents the cold temperature end of the temperature range, the second represents the upper limit of the operating temperature range and the third symbol represents the capacitance change allowed over the operating temperature range. Table 1 provides a detailed explanation of the EIA system.

**Effects of Voltage –** Variations in voltage have little effect on Class 1 dielectric but does affect the capacitance and dissipation factor of Class 2 dielectrics. The application of DC voltage reduces both the capacitance and dissipation factor while the application of an AC voltage within a reasonable range tends to increase both capacitance and dissipation factor readings. If a high enough AC voltage is applied, eventually it will reduce capacitance just as a DC voltage will. Figure 2 shows the effects of AC voltage.

![](_page_66_Figure_8.jpeg)

![](_page_66_Figure_9.jpeg)

*Figure 2*

Capacitor specifications specify the AC voltage at which to measure (normally 0.5 or 1 VAC) and application of the wrong voltage can cause spurious readings. Figure 3 gives the voltage coefficient of dissipation factor for various AC voltages at 1 kilohertz. Applications of different frequencies will affect the percentage changes versus voltages.

**D.F. vs. A.C. Measurement Volts**

![](_page_66_Figure_12.jpeg)

Typical effect of the application of DC voltage is shown in Figure 4. The voltage coefficient is more pronounced for higher K dielectrics. These figures are shown for room temperature conditions. The combination characteristic known as voltage temperature limits which shows the effects of rated voltage over the operating temperature range is shown in Figure 5 for the military BX characteristic.

![](_page_66_Picture_14.jpeg)

![](_page_67_Picture_1.jpeg)

![](_page_67_Figure_2.jpeg)

![](_page_67_Figure_3.jpeg)

**Effects of Time –** Class 2 ceramic capacitors change capacitance and dissipation factor with time as well as temperature, voltage and frequency. This change with time is known as aging. Aging is caused by a gradual re-alignment of the crystalline structure of the ceramic and produces an exponential loss in capacitance and decrease in dissipation factor versus time. A typical curve of aging rate for semistable ceramics is shown in Figure 6.

If a Class 2 ceramic capacitor that has been sitting on the shelf for a period of time, is heated above its curie point, (125°C for 4 hours or 150°C for 1 ⁄2 hour will suffice) the part will de-age and return to its initial capacitance and dissipation factor readings. Because the capacitance changes rapidly, immediately after de-aging, the basic capacitance measurements are normally referred to a time period sometime after the de-aging process. Various manufacturers use different time bases but the most popular one is one day or twenty-four hours after "last heat." Change in the aging curve can be caused by the application of voltage and other stresses. The possible changes in capacitance due to de-aging by heating the unit explain why capacitance changes are allowed after test, such as temperature cycling, moisture resistance, etc., in MIL specs. The application of high voltages such as dielectric withstanding voltages also

tends to de-age capacitors and is why re-reading of capacitance after 12 or 24 hours is allowed in military specifications after dielectric strength tests have been performed.

![](_page_67_Figure_7.jpeg)

**Effects of Frequency –** Frequency affects capacitance and impedance characteristics of capacitors. This effect is much more pronounced in high dielectric constant ceramic formulation than in low K formulations. AVX's SpiCap software generates impedance, ESR, series inductance, series resonant frequency and capacitance all as functions of frequency, temperature and DC bias for standard chip sizes and styles. It is available free from AVX and can be downloaded for free from AVX website: www.avx.com.

![](_page_67_Picture_9.jpeg)

![](_page_68_Picture_1.jpeg)

**Effects of Mechanical Stress –** High "K" dielectric ceramic capacitors exhibit some low level piezoelectric reactions under mechanical stress. As a general statement, the piezoelectric output is higher, the higher the dielectric constant of the ceramic. It is desirable to investigate this effect before using high "K" dielectrics as coupling capacitors in extremely low level applications.

**Reliability –** Historically ceramic capacitors have been one of the most reliable types of capacitors in use today. The approximate formula for the reliability of a ceramic capacitor is:

$$
\frac{L_o}{L_t} = \left(\frac{V_t}{V_o}\right)^{\chi} \left(\frac{T_t}{T_o}\right)^{\gamma}
$$

where

 $L_0$  = operating life **T**<sub>t</sub> = test temperature and  $L_t$  = test life **T**<sub>o</sub> = operating temperature  $T_o$  = operating temperature<br>in  ${}^{\circ}C$  $V_t$  = test voltage in °C<br>  $V_o$  = operating voltage  $X, Y$  = see text **V<sub>o</sub>** = operating voltage

Historically for ceramic capacitors exponent X has been considered as 3. The exponent Y for temperature effects typically tends to run about 8.

A capacitor is a component which is capable of storing electrical energy. It consists of two conductive plates (electrodes) separated by insulating material which is called the dielectric. A typical formula for determining capacitance is:

$$
C = \frac{.224 \text{ KA}}{t}
$$

- **C** = capacitance (picofarads)
- $K =$  dielectric constant (Vacuum = 1)
- $A = area$  in square inches
- **t** = separation between the plates in inches (thickness of dielectric)
- **.224** = conversion constant
	- (.0884 for metric system in cm)

**Capacitance –** The standard unit of capacitance is the farad. A capacitor has a capacitance of 1 farad when 1 coulomb charges it to 1 volt. One farad is a very large unit and most capacitors have values in the micro  $(10<sup>-6</sup>)$ , nano  $(10<sup>-9</sup>)$  or pico  $(10<sup>-12</sup>)$  farad level.

**Dielectric Constant –** In the formula for capacitance given above the dielectric constant of a vacuum is arbitrarily chosen as the number 1. Dielectric constants of other materials are then compared to the dielectric constant of a vacuum.

**Dielectric Thickness –** Capacitance is indirectly proportional to the separation between electrodes. Lower voltage requirements mean thinner dielectrics and greater capacitance per volume.

**Area –** Capacitance is directly proportional to the area of the electrodes. Since the other variables in the equation are usually set by the performance desired, area is the easiest parameter to modify to obtain a specific capacitance within a material group.

**Energy Stored –** The energy which can be stored in a capacitor is given by the formula:

 $E = \frac{1}{2}CV^2$ 

 $E =$  energy in joules (watts-sec)

**V** = applied voltage

**C** = capacitance in farads

**Potential Change –** A capacitor is a reactive component which reacts against a change in potential across it. This is shown by the equation for the linear charge of a capacitor:

$$
I_{\text{ideal}} = C \frac{dV}{dt}
$$

where

 $I =$  Current

**C** = Capacitance

**dV/dt** = Slope of voltage transition across capacitor

Thus an infinite current would be required to instantly change the potential across a capacitor. The amount of current a capacitor can "sink" is determined by the above equation.

**Equivalent Circuit –** A capacitor, as a practical device, exhibits not only capacitance but also resistance and inductance. A simplified schematic for the equivalent circuit is:

![](_page_68_Figure_33.jpeg)

**Reactance –** Since the insulation resistance  $(R_n)$  is normally very high, the total impedance of a capacitor is:

$$
Z = \sqrt{R_s^2 + (X_c - X_L)^2}
$$
  
where  

$$
Z = \text{Total Impedance}
$$

**z** nce **R**<sub>s</sub> = Series Resistance  $X_c$  = Capacitive Reactance  $\overline{2 \pi f}C$  $X<sub>i</sub>$  = Inductive Reactance = 2 π fL

The variation of a capacitor's impedance with frequency determines its effectiveness in many applications.

**Phase Angle –** Power Factor and Dissipation Factor are often confused since they are both measures of the loss in a capacitor under AC application and are often almost identical in value. In a "perfect" capacitor the current in the capacitor will lead the voltage by 90°.

![](_page_68_Picture_39.jpeg)

![](_page_69_Picture_1.jpeg)

![](_page_69_Figure_2.jpeg)

In practice the current leads the voltage by some other phase angle due to the series resistance  $R<sub>s</sub>$ . The complement of this angle is called the loss angle and:

> Power Factor (P.F.) =  $\cos \phi$  or Sine  $\delta$ Dissipation Factor (D.F.) = tan  $\delta$

for small values of  $\delta$  the tan and sine are essentially equal which has led to the common interchangeability of the two terms in the industry.

**Equivalent Series Resistance –** The term E.S.R. or Equivalent Series Resistance combines all losses both series and parallel in a capacitor at a given frequency so that the equivalent circuit is reduced to a simple R-C series connection.

![](_page_69_Figure_7.jpeg)

**Dissipation Factor –** The DF/PF of a capacitor tells what percent of the apparent power input will turn to heat in the capacitor.

$$
Dissipation Factor = \frac{E.S.R.}{X_c} = (2 \pi fC) (E.S.R.)
$$

The watts loss are:

**Watts loss** = **(2** π **fCV2 ) (D.F.)**

Very low values of dissipation factor are expressed as their reciprocal for convenience. These are called the "Q" or Quality factor of capacitors.

**Parasitic Inductance –** The parasitic inductance of capacitors is becoming more and more important in the decoupling of today's high speed digital systems. The relationship between the inductance and the ripple voltage induced on the DC voltage line can be seen from the simple inductance equation:

$$
V = L \frac{di}{dt}
$$

The  $\frac{dl}{dt}$  seen in current microprocessors can be as high as 0.3 A/ns, and up to 10A/ns. At 0.3 A/ns, 100pH of parasitic inductance can cause a voltage spike of 30mV. While this does not sound very drastic, with the Vcc for microprocessors decreasing at the current rate, this can be a fairly large percentage.

Another important, often overlooked, reason for knowing the parasitic inductance is the calculation of the resonant frequency. This can be important for high frequency, bypass capacitors, as the resonant point will give the most signal attenuation. The resonant frequency is calculated from the simple equation:

$$
f_{res} = \frac{1}{2\pi\sqrt{LC}}
$$

**Insulation Resistance –** Insulation Resistance is the resistance measured across the terminals of a capacitor and consists principally of the parallel resistance  $\mathsf{R}_P$  shown in the equivalent circuit. As capacitance values and hence the area of dielectric increases, the I.R. decreases and hence the product (C x IR or RC) is often specified in ohm faradsor more commonly megohm-microfarads. Leakage current is determined by dividing the rated voltage by IR (Ohm's Law).

**Dielectric Strength –** Dielectric Strength is an expression of the ability of a material to withstand an electrical stress. Although dielectric strength is ordinarily expressed in volts, it is actually dependent on the thickness of the dielectric and thus is also more generically a function of volts/mil.

**Dielectric Absorption –** A capacitor does not discharge instantaneously upon application of a short circuit, but drains gradually after the capacitance proper has been discharged. It is common practice to measure the dielectric absorption by determining the "reappearing voltage" which appears across a capacitor at some point in time after it has been fully discharged under short circuit conditions.

**Corona –** Corona is the ionization of air or other vapors which causes them to conduct current. It is especially prevalent in high voltage units but can occur with low voltages as well where high voltage gradients occur. The energy discharged degrades the performance of the capacitor and can in time cause catastrophic failures.

# **Surface Mounting Guide**

![](_page_70_Picture_1.jpeg)

## **MLC Chip Capacitors**

## **REFLOW SOLDERING**

![](_page_70_Picture_279.jpeg)

## **Component Pad Design**

Component pads should be designed to achieve good solder filets and minimize component movement during reflow soldering. Pad designs are given below for the most common sizes of multilayer ceramic capacitors for both wave and reflow soldering. The basis of these designs is:

- Pad width equal to component width. It is permissible to decrease this to as low as 85% of component width but it is not advisable to go below this.
- Pad overlap 0.5mm beneath component.
- Pad extension 0.5mm beyond components for reflow and 1.0mm for wave soldering.

## **WAVE SOLDERING**

![](_page_70_Figure_11.jpeg)

![](_page_70_Picture_280.jpeg)

## **Component Spacing**

For wave soldering components, must be spaced sufficiently far apart to avoid bridging or shadowing (inability of solder to penetrate properly into small spaces). This is less important for reflow soldering but sufficient space must be allowed to enable rework should it be required.

![](_page_70_Figure_15.jpeg)

### **Preheat & Soldering**

The rate of preheat should not exceed 4°C/second to prevent thermal shock. A better maximum figure is about 2°C/second.

For capacitors size 1206 and below, with a maximum thickness of 1.25mm, it is generally permissible to allow a temperature differential from preheat to soldering of 150°C. In all other cases this differential should not exceed 100°C.

For further specific application or process advice, please consult AVX.

### **Cleaning**

Care should be taken to ensure that the capacitors are thoroughly cleaned of flux residues especially the space beneath the capacitor. Such residues may otherwise become conductive and effectively offer a low resistance bypass to the capacitor.

Ultrasonic cleaning is permissible, the recommended conditions being 8 Watts/litre at 20-45 kHz, with a process cycle of 2 minutes vapor rinse, 2 minutes immersion in the ultrasonic solvent bath and finally 2 minutes vapor rinse.

![](_page_70_Picture_23.jpeg)

# **Surface Mounting Guide**

## **MLC Chip Capacitors**

## **APPLICATION NOTES**

### **Storage**

Good solderability is maintained for at least twelve months, provided the components are stored in their "as received" packaging at less than 40°C and 70% RH.

### **Solderability**

Terminations to be well soldered after immersion in a 60/40 tin/lead solder bath at  $235 + 5^{\circ}$ C for  $2 + 1$  seconds.

### **Leaching**

Terminations will resist leaching for at least the immersion times and conditions shown below.

![](_page_71_Picture_394.jpeg)

## **Recommended Soldering Profiles**

### **Reflow**

![](_page_71_Figure_12.jpeg)

### **Lead-Free Reflow Profile**

![](_page_71_Figure_14.jpeg)

![](_page_71_Figure_15.jpeg)

![](_page_71_Figure_16.jpeg)

T/maximum 150°C

## **Lead-Free Wave Soldering**

The recommended peak temperature for lead-free wave soldering is 250°C-260°C for 3-5 seconds. The other parameters of the profile remains the same as above.

The following should be noted by customers changing from lead based systems to the new lead free pastes.

- a) The visual standards used for evaluation of solder joints will need to be modified as lead free joints are not as bright as with tin-lead pastes and the fillet may not be as large.
- b) Resin color may darken slightly due to the increase in temperature required for the new pastes.
- c) Lead-free solder pastes do not allow the same self alignment as lead containing systems. Standard mounting pads are acceptable, but machine set up may need to be modified.

### **General**

Surface mounting chip multilayer ceramic capacitors are designed for soldering to printed circuit boards or other substrates. The construction of the components is such that they will withstand the time/temperature profiles used in both wave and reflow soldering methods.

### **Handling**

Chip multilayer ceramic capacitors should be handled with care to avoid damage or contamination from perspiration and skin oils. The use of tweezers or vacuum pick ups is strongly recommended for individual components. Bulk handling should ensure that abrasion and mechanical shock are minimized. Taped and reeled components provides the ideal medium for direct presentation to the placement machine. Any mechanical shock should be minimized during handling chip multilayer ceramic capacitors.

### **Preheat**

It is important to avoid the possibility of thermal shock during soldering and carefully controlled preheat is therefore required. The rate of preheat should not exceed 4°C/second

![](_page_71_Picture_30.jpeg)

![](_page_71_Picture_32.jpeg)
# **Surface Mounting Guide**



# **MLC Chip Capacitors**

and a target figure 2°C/second is recommended. Although an 80°C to 120°C temperature differential is preferred, recent developments allow a temperature differential between the component surface and the soldering temperature of 150°C (Maximum) for capacitors of 1210 size and below with a maximum thickness of 1.25mm. The user is cautioned that the risk of thermal shock increases as chip size or temperature differential increases.

#### **Soldering**

Mildly activated rosin fluxes are preferred. The minimum amount of solder to give a good joint should be used. Excessive solder can lead to damage from the stresses caused by the difference in coefficients of expansion between solder, chip and substrate. AVX terminations are suitable for all wave and reflow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

#### **Cooling**

Natural cooling in air is preferred, as this minimizes stresses within the soldered joint. When forced air cooling is used, cooling rate should not exceed 4°C/second. Quenching is not recommended but if used, maximum temperature differentials should be observed according to the preheat conditions above.

#### **Cleaning**

Flux residues may be hygroscopic or acidic and must be removed. AVX MLC capacitors are acceptable for use with all of the solvents described in the specifications MIL-STD-202 and EIA-RS-198. Alcohol based solvents are acceptable and properly controlled water cleaning systems are also acceptable. Many other solvents have been proven successful, and most solvents that are acceptable to other components on circuit assemblies are equally acceptable for use with ceramic capacitors.

## **POST SOLDER HANDLING**

Once SMP components are soldered to the board, any bending or flexure of the PCB applies stresses to the soldered joints of the components. For leaded devices, the stresses are absorbed by the compliancy of the metal leads and generally don't result in problems unless the stress is large enough to fracture the soldered connection.

Ceramic capacitors are more susceptible to such stress because they don't have compliant leads and are brittle in nature. The most frequent failure mode is low DC resistance or short circuit. The second failure mode is significant loss of capacitance due to severing of contact between sets of the internal electrodes.

Cracks caused by mechanical flexure are very easily identified and generally take one of the following two general forms:



Type A: Angled crack between bottom of device to top of solder joint.



Type B: Fracture from top of device to bottom of device.

Mechanical cracks are often hidden underneath the termination and are difficult to see externally. However, if one end termination falls off during the removal process from PCB, this is one indication that the cause of failure was excessive mechanical stress due to board warping.





## **MLC Chip Capacitors**

## **COMMON CAUSES OF MECHANICAL CRACKING**

The most common source for mechanical stress is board depanelization equipment, such as manual breakapart, vcutters and shear presses. Improperly aligned or dull cutters may cause torqueing of the PCB resulting in flex stresses being transmitted to components near the board edge. Another common source of flexural stress is contact during parametric testing when test points are probed. If the PCB is allowed to flex during the test cycle, nearby ceramic capacitors may be broken.

A third common source is board to board connections at vertical connectors where cables or other PCBs are connected to the PCB. If the board is not supported during the plug/unplug cycle, it may flex and cause damage to nearby components.

Special care should also be taken when handling large (>6" on a side) PCBs since they more easily flex or warp than smaller boards.

## **REWORKING OF MLCs**

Thermal shock is common in MLCs that are manually attached or reworked with a soldering iron. *AVX strongly recommends that any reworking of MLCs be done with hot air reflow rather than soldering irons.* It is practically impossible to cause any thermal shock in ceramic capacitors when using hot air reflow.

However direct contact by the soldering iron tip often causes thermal cracks that may fail at a later date. If rework by soldering iron is absolutely necessary, it is recommended that the wattage of the iron be less than 30 watts and the tip temperature be <300ºC. *Rework should be performed by applying the solder iron tip to the pad and not directly contacting any part of the ceramic capacitor.*



Preferred Method - No Direct Part Contact Poor Nethod - Direct Contact with Part

## **PCB BOARD DESIGN**

To avoid many of the handling problems, AVX recommends that MLCs be located at least .2" away from nearest edge of board. However when this is not possible, AVX recommends that the panel be routed along the cut line, adjacent to where the MLC is located.





No Stress Relief for MLCs **Routed Cut Line Relieves Stress on MLC** 



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